Application Note Metals



Analysis of Steel and Its Alloys by ICP-OES Following the GB/T 20125-2006 Standard

Accurate, robust, and stable measurements using the Agilent 5800 VDV ICP-OES and AVS 7 sampling valve



Introduction

Elemental impurities in steel or steel alloys can affect the performance of the final product. So, steel manufacturers conduct rigorous quality control (QC) testing for a range of metals and trace elements to ensure the grade and price of their final products. There are various standard methods that relate to the QC of manufactured steel products, including the Standardization Administration of China GB/T 20125-2006 standard. The GB/T standard uses ICP-OES to determine multiple elements in low-alloy steel (1).

Author

Peter Riles, Agilent Technologies, Inc. Different grades of steel have different specifications for elemental content. Most steel and stainless-steel grades are required to have less than 0.05% by weight of sulfur (S) and less than 0.04% by weight of phosphorus (P). In addition to measuring low-level contaminants, such as S and P, labs are also required to provide quantitative results for major components such as nickel (Ni) and iron (Fe).

Nowadays, laboratories demand more from their instrumentation than simply measuring elements in a sample over a wide dynamic range. Many QC laboratories process hundreds of samples per day, so achieving high sample throughput with easy-to-use and reliable instrumentation is critical. High levels of accuracy, stability, and robustness are also needed to reduce the time spent remeasuring samples so that analysts can focus on more productive tasks. Typically, samples are remeasured because of an instrumentrelated problem or sample-related problem.

To prevent the most common causes of having to remeasure a sample, the Agilent 5800 ICP-OES and Agilent 5900 ICP-OES use a series of tools that provide useful information on samples, methods, and the operational status of the instrument. Features such as IntelliQuant, IntelliQuant Screening, and Early Maintenance Feedback (EMF) (2-4)improve data accuracy and reduce unscheduled downtime for maintenance, providing labs with greater confidence in the method and results. If selected, IntelliQuant Screening is run independently, as a standalone method.

Also, spectral interferences arising from the complex elemental content of stainless-steel sample matrices especially line-rich Fe—can impact the accuracy of the data for some analyte elements such as S. The 5800 and 5900 ICP-OES include freeform optics to enhance spectral resolution and an advanced detector that lowers detection limits. The higher resolution optics mean that more analyte lines are separated from neighboring lines, enabling the 5800 or 5900 to achieve lower detection limits for elements in complex matrices. To resolve interferences, Agilent ICP Expert software includes the widest range of background correction techniques for ICP-OES. For an element like Al, which isn't affected by directly overlapping interferences, Fitted Background Correction (FBC) can be used to improve the accuracy of the measurement (5). FBC is the simplest correction method, requiring no setup. To resolve interferences arising from more complex background signals, Fast Automated Curve Fitting Technique (FACT) is a powerful technique that ensures accurate results (6). When direct overlaps are observed in the spectrum, inter-element correction factors and off-peak background correction can be used.

In this study, an Agilent 5800 Vertical Dual View (VDV) ICP-OES was used to measure 15 elements in three stainless steel certified reference materials (CRMs) in accordance with the GB/T 20125-2006 standard. The CRMs were prepared by microwave acid digestion.

Experimental

Instrumentation

All measurements were performed using a 5800 VDV ICP-OES fitted with a SeaSpray concentric nebulizer, double-pass cyclonic spray chamber, and an Agilent Easy-fit demountable VDV torch with a 1.8 mm injector. The instrument was configured with an integrated Advanced Valve System (AVS 7) seven-port switching valve and an Agilent SPS 4 autosampler. The AVS 7 uses a high-speed positive displacement pump to rapidly fill the sample loop, speeding up the analysis and reducing argon consumption (7). The valve also reduces maintenance and cleaning requirements of the torch, as less sample passes through the sample introduction system compared to conventional sample introduction.

The Vista Chip III detector of the 5800 provides high-speed continuous wavelength coverage from 167 to 785 nm, ensuring that a suitable, interference-free line can be found for most analytes. There is no time penalty when adding extra wavelengths for an element to the analysis. The wide range of the detector enables both major (e.g., Ni and Fe) and trace elements (e.g., S and P) to be analyzed in the same sample digest, avoiding the need to perform multiple dilutions.

Internal standard correction was used to correct for matrix and easily ionizable element (EIE) interferences. Europium (Eu) and lutetium (Lu) were used as internal standards, each at a concentration of 10 mg/L.

The instrument and method parameters for the 5800 VDV ICP-OES are given in Table 1 and the AVS 7 settings are given in Table 2.

Table 1. Agilent 5800 VDV ICP-OES instrument and method parameters.

Parameter	Radial	Axial			
Read Time (s)	5	20			
Replicates	3	3			
Sample Uptake Delay (s)	()			
Stabilization Time (s)	10	0			
Rinse Time (s)	()			
Pump Speed (rpm)	12				
RF Power (kW)	1.5				
Auxillary Flow (L/min)	1				
Plasma Flow (L/min)	12				
Nebulizer Flow (L/min)	0.8				
Viewing Height (mm)	8	NA			
Sample Pump Tubing	White-white				
Internal Standard Pump Tubing	Black-black				
Waste Pump Tubing	Blue-blue				
Background Correction	FBC/FACT/Off-peak				

Table 2. AVS 7 switching valve system parameters.

Parameter	Setting
Sample Loop Size (mL)	1.5
Pump Rate - Uptake (mL/min)	36
Pump Rate - Inject (mL/min)	5
Valve Uptake Delay (s)	7
Bubble Inject Time (s)	2
Pre-emptive Rinse Time (s)	1

Samples

Three steel CRMs, GH-135 6934 and GSBH 40031-93 (China National Analysis Center for Iron and Steel), and BCS-336 (British Chemical Standards), were used to validate the 5800 VDV ICP-OES method. Pure iron wire (≥99.99% trace metal basis, Sigma Aldrich) was used as a blank sample.

Sample preparation

The samples were prepared by microwave digestion using a Mars 6 Microwave Digestion System (CEM Corporation, NC, USA). First, 0.25 g of each CRM was digested in 1 mL H₂0, 3 mL of HNO₃, 1 mL H₂O₂, and 9 mL of HCl using the microwave digestion program shown in Table 3. The digests were then made up to a volume of 50 mL with 18 M Ω de-ionized water (DIW) to give a final matrix of 24% aqua regia. A method blank was prepared at the same time as the CRMs, using the same method to digest 6N high purity iron wire. This method blank solution was prepared with a final concentration of 5000 mg/L of Fe.

Table 3. Microwave digestion parameters.

Parameter	Value
Power (W)	0-1200
Temperature (°C)	200
Ramp Time (min)	25
Hold Time (min)	20

Wavelength selection using IntelliQuant Screening

IntelliQuant Screening allows analysts to run a quick, semiquantitative screening of unknown samples, and is especially useful for samples with a complex matrix (3). In this study, IntelliQuant Screening was used during method development, particularly for wavelength selection, and to determine the approximate concentration of elements in some of the steel CRM digests.

Figure 1 shows the IntelliQuant Screening results for As in the BCS-336 steel CRM. The IntelliQuant algorithm automatically identified 197.198 nm as the best As wavelength to use in the quantitative method, as indicated by the highest star rating and 'green' tick.

Element	Used	Flags	Wavelength	Rating	Concentration	Intensity	Background
As							
			188.980	*	221.63	1397.6	1686.5
			193.696	**	289.12	1707.8	1979.8
	~		197.198	***	264.05	1167.8	2592.0
			228.812	**	193.97	605.7	3709.6

Figure 1. Star ranking of As lines in the BCS-336 CRM.

The IntelliQuant Screening wavelength star rankings for Ni in the GSBH 40031-93 and BCS-336 steel CRMs show that Ni 231.604 nm is the preferred line in both matrices (Figures 2 and 3). The IntelliQuant semiquantitative concentration for Ni 231.604 nm of 264.84 mg/kg is in close agreement with the GSBH 40031-93 certified Ni concentration of 260 mg/kg. The BCS 336 CRM contains Ni at a higher concentration than GSBH 40031-93, but the IntelliQuant result for Ni of 89,500 mg/kg compares reasonably well with the certified value of 94,800 mg/kg. The IntelliQuant Screening results shown in Figures 2 and 3 highlight the linearity of the 5800 VDV ICP-OES, as both measurements selected the same wavelength for Ni at a low and high concentration.

Element	Used	Flags	Wavelength	Rating		Concentration	Intensity	Background
Ni								
	~		231.604	****		264.84	8625.6	4331.7
			216.555	*	?	373.45	6411.4	3758.6
			227.021	****		272.14	7907.7	5670.2
			222.486	***		288.90	2193.0	2953.7
			222.295	***		261.49	1712.9	2794.4

Figure 2. IntelliQuant Screening star ranking for Ni in the GSBH 40031-93 CRM.

Flags	Wavelength	Rating		Concentration	Intensity	Background
	231.604	****		8.95E+004	3025326.5	8922.4
	216.555	*	?	1.03E+005	1841555.8	9203.5
	221.648	*	?	1.17E+005	2403467.4	4859.2
	230.299	*****		9.87E+004	2146210.8	10233.3
	222.486	*****		9.35E+004	738226.0	4446.2
	222.295	*****		9.31E+004	616946.9	3691.8
		Flags Wavelength 231.604 216.555 221.648 230.299 222.486 222.295	231.604 ***** 216.555 * 221.648 * 230.299 ***** 222.486 *****	231.604 ***** 216.555 * ? 221.648 * ? 230.299 ***** 222.486 *****	231.604 ***** 8.95E+004 216.555 * ? 1.03E+005 221.648 * ? 1.17E+005 230.299 ***** 9.87E+004 222.486 ***** 9.35E+004	231.604 ***** 8.95E+004 3025326.5 216.555 * ? 1.03E+005 1841555.8 221.648 * ? 1.17E+005 2403467.4 230.299 ***** 9.87E+004 2146210.8 222.486 ***** 9.35E+004 738226.0

Figure 3. IntelliQuant Screening star ranking for Ni in the BCS-336 CRM.

Calibration

Matrix matched calibration standards were prepared from Agilent 10,000 mg/L single element stock solutions in a matrix of 24% aqua regia. The concentration range used for the elements was based on IntelliQuant Screening data and on the expected concentrations to be found in samples from previous studies. Linear calibrations were acquired for all elements, as indicated by the correlation coefficients of greater than 0.999 (Table 4). The calibration blank was made in the same matrix as the calibration standards.

 Table 4. Concentration of calibration standards and calibration correlation coefficients.

Element	Std 1	Std 2	Std 3	Std 4	Std 5	Std 6	Std 7	Std 8	Std 9	Std 10	Correlation Coefficient
mg/L											
Al	2	20	200								1.00000
As							0.1	1	10		1.00000
В				0.5	5	50					1.00000
Со				0.5	5	50					0.99981
Cr	10	100	1000								0.99993
Cu	0.5	5	50								1.00000
Fe										5000	1.00000
Mn							1	10	100		1.00000
Мо				2	20	200					0.99999
Ni							20	200	2000		0.99994
Р	0.1	1	10								1.00000
S	0.1	1	10								0.99999
Si				1	10	100					0.99999
Ti							2	20	200		1.00000
V				0.5	5	50					1.00000

Quality control

A midrange calibration standard was used as the continuing calibration verification (CCV) sample to check the long-term stability of the instrument.

Background correction and interference correction

To reduce the impact of spectral interferences arising from the sample matrices, different background correction methods were used. For elements where there were no direct overlaps, FBC was used. An example of FBC for Al 396.152 nm is shown in Figure 4.

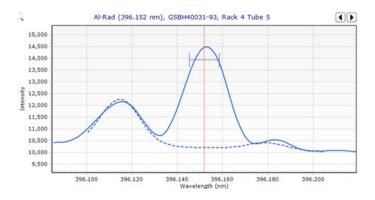


Figure 4. Fitted background correction for AI 396.152 nm.

For elements that were affected by more complex background signals, FACT was used. In these instances, a 5000 mg/L Fe solution was used as a matrix in the FACT models. Figure 5 shows a FACT model for Co 230.786 nm with corrections for Cr 230.752 nm, Ni 230.778 nm, Mo 230.798 nm, and Ni 230.817 nm. FACT has accurately modeled the interfering peaks and resolved the analyte signal, providing accurate results for Co.

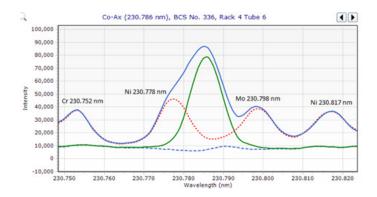


Figure 5. FACT model for Co 230.786 nm.

Due to the complexity of steel samples, many direct spectral overlaps can be present. To correct for a direct spectral overlap, a mathematical approach, rather than a graphical approach is required. The contribution to the total signal at the analyte wavelength that is determined to be from the interfering signal is subtracted from the total signal. This approach relies on having a fixed background so that the calculations are consistent. Off-peak background correction was used for S 181.972 and an inter-element correction (IEC) calculation was applied.

Results and discussion

Method detection limits

Method detection limits (MDLs) were determined by analyzing a 5000 mg/L iron blank solution 10 times on three days. The MDL was calculated as three sigma of the blank concentration determined for each element (apart from iron) multiplied by the dilution factor. The MDLs in Table 5 are reported on an in-sample basis.

Element	Background Correction Method	Wavelength (nm)	MDL (mg/kg)
AI	FBC	396.152	2.04
As	FACT	197.198	2.19
В	FBC	182.577	0.988
Со	FACT	230.786	0.284
Cr	FBC	267.716	0.475
Cu	FACT	327.395	0.163
Mn	FBC	257.61	0.689
Мо	FBC	202.032	0.721
Ni	FBC	231.604	1.49
Р	Off-peak	178.222	1.24
S	Off-peak	181.972	2.26
Si	FBC	251.611	1.51
Ti	FBC	337.28	0.545
V	FACT	311.837	0.217

Table 5. Method detection limits for all elements in a 5000 mg/L iron blank solution.

Accuracy of the method

To validate the sample preparation procedure and the accuracy of the 5800 VDV ICP-OES method, the three CRMs were analyzed in triplicate and the average of the results was calculated. The results in Table 6 show excellent recoveries within $\pm 10\%$ of the certified value, demonstrating the accuracy of the method for the analysis of samples with complex matrices. The results also show the robustness and analytical range of the 5800 ICP-OES to measure high concentration elements such as Ni, Fe, and Cr in the same run as trace elements such as As, B, Co, P, and S.

Long-term stability

The long-term stability (LTS) of this application was tested by analyzing 217 CRM samples over six hours by 5800 VDV ICP-OES. A QC solution was measured after every 10 samples and the recoveries are shown in Figure 6. All measurements were within $\pm 10\%$ of the expected concentrations, demonstrating the excellent robustness and stability of the 5800 ICP-OES for the analysis of high matrix steel sample digests over six hours.

GH 135 GSBH40031-93 BCS No. 336 Element, Wavelength Certified Certified Measured Certified Measured Recovery Measured Recovery Recovery (nm) (mg/kg) (mg/kg) (%) (mg/kg) (mg/kg) (%) (mg/kg) (mg/kg) (%) AI 396.152 30390 31500 96 170.4 170 100 1058 As 197.198 54.99 65.76 66 100 232 B 182.577 83.19 87 96 1.471 3.248 Co 230.786 35.21 57.56 99 593.7 94 58 630 Cr 267.716 132200 139400 95 363.4 350 104 163300 176000 93 1120 Cu 327.395 228.1 314.4 340 92 1100 102 Fe 273.358 405100 962700 674400 Mn 257.61 4146 5167 7719 4500 92 5500 94 8100 95 Mo 202.032 16840 18400 92 54.23 59 92 23120 24300 95 Ni 231.604 337700 95910 94800 358500 94 283.6 260 109 101 P 178.222 36.52 40 91 101 200 106 171.8 170 211.3 S 181.972 38.65 37 104 159.6 170 94 244.6 230 106 105 Si 251.611 4793 4520 106 2281 2280 100 5359 5100 Ti 337.28 22080 24490 90 12.65 57.73 V 311.837 1202 6.838 300.9 300 100

Table 6. Recoveries for elements in three steel CRMs. Blank cells indicate no certified or reference value.

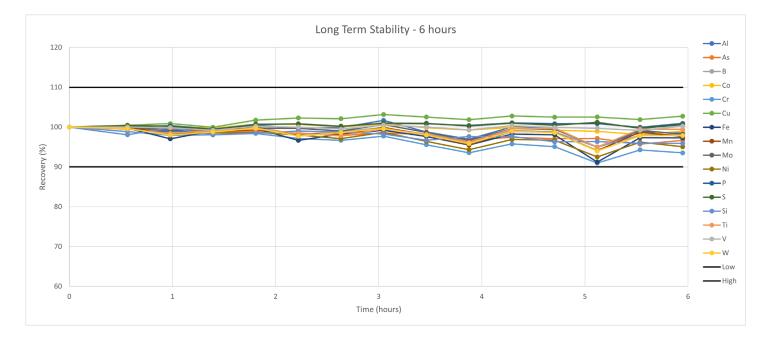


Figure 6. Stability of trace elements in a QC sample analyzed after each block of 10 steel digest samples over six hours.

Conclusion

The Agilent 5800 VDV ICP-OES with high-resolution optics and continuous wavelength range detector was used to analyze multiple elements in three steel CRMs, prepared using microwave acid digestion. The method was based on the GB/T 20125-2006 standard for the elemental determination of low-alloy steel.

The Fe content of steel digests can be problematic due to the high number of Fe lines in the ICP-OES spectra that interfere with analytes such as sulfur. To help with method development, IntelliQuant Screening semiquantitative data was used to select or confirm the best wavelengths for some elements. The IntelliQuant Screening data was also used to help with selecting the best background correction technique for the analytes in this application.

The method showed good accuracy and dynamic range as all major (percent-level) components and trace (ppm in the solid) elements in the three CRMs recovered within $\pm 10\%$ of the certified values. The matrix tolerance and robustness of the 5800 was shown by the excellent recoveries of trace elements measured throughout the analysis of high matrix steel sample digests over six hours.

The study has demonstrated that the 5800 VDV ICP-OES fitted with an AVS 7 sampling valve is suitable for the routine analysis of steel digest samples, in accordance with industry standard methods.

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